MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PLED

MSESD0522P

Product specification





Features

- 150Watts peak pulse power (tp = 8/20µs)
- SLP1610-4 package
- Bidirectional configurations
- Solid-state silicon-avalanche technology
- Low clamping voltage
- Low leakage current
- Low capacitance (Cj=0.3pF typ. IO to IO)
- Protection one data/power line to:
- IEC 61000-4-2 ±15kV contact ±20kV air
- IEC 61000-4-4 (EFT) 40A (5/50ns)
- IEC 61000-4-5 (Lightning) 4A (8/20μs)

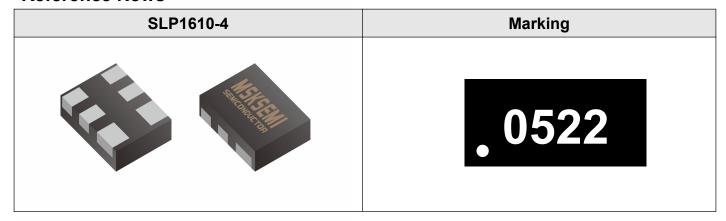
Mechanical Data

- SLP1610-4 package
- Molding compound flammability rating: UL 94V-0
- Packaging: Tape and Reel
- RoHS/WEEE Compliant

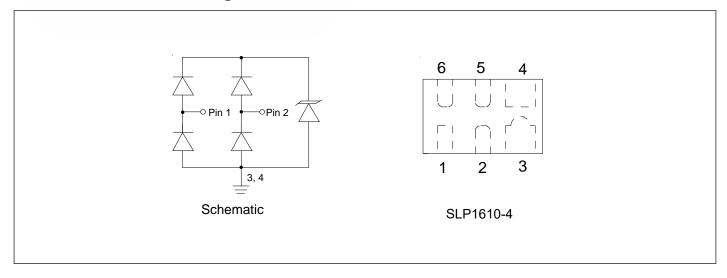
Applications

- Digital Visual Interface (DVI)
- MDDI Ports
- PCI Express
- eSATA Interface

Reference News



Schematic & PIN Configuration





Absolute Maximum Rating

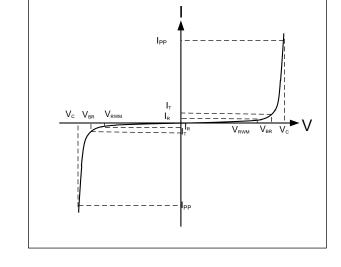
Rating	Symbol	Value	Units
Peak Pulse Power (t _p =8/20µs)	P _{PP}	150	Watts
Peak Pulse Current (t _p =8/20μs) (note1)	I _{pp}	4.0	А
ESD per IEC 61000-4-2 (Air) ESD per IEC 61000-4-2 (Contact)	V _{ESD}	20 15	kV
Lead Soldering Temperature	T∟	260(10seconds)	$^{\circ}$ C
Junction Temperature	TJ	-55 to + 125	$^{\circ}$
Storage Temperature	T_{stg}	-55 to + 125	$^{\circ}$

Electrical Characteristics

Parameter	Symbol	Conditions	Min	Typical	Max	Units
Reverse Stand-Off Voltage	V _{RWM}				5.0	V
Reverse Breakdown Voltage	V_{BR}	I _T =1mA	6.0			V
Reverse Leakage Current	I _R	V _{RWM} =5V,T=25℃			1.0	μA
Peak Pulse Current	I _{PP}	tp =8/20µs			4.0	Α
Clamping Voltage	Vc	I _{PP} =1A,t _p =8/20μs			15	V
Junction Capacitance	C _j	IO to IO V _R = 0V, f= 1MHz		0.3	0.5	pF

Electrical Parameters (TA = 25°C unless otherwise noted)

Symbol	Parameter
I PP	Maximum Reverse Peak Pulse Current
Vc	Clamping Voltage @ IPP
VRWM	Working Peak Reverse Voltage
lR	Maximum Reverse Leakage Current @ VRWM
V _{BR}	Breakdown Voltage @ I⊤
lτ	Test Current



Note: $8/20\mu s$ pulse waveform.



TypicalCharacteristics

Figure 1: Peak Pulse Power vs. Pulse Time

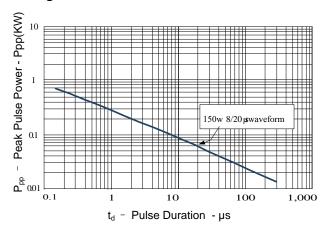


Figure3: Pulse Waveform

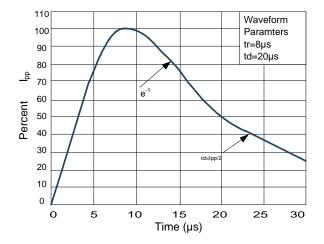


Figure 2: Power Derating Curve

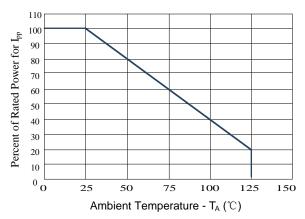
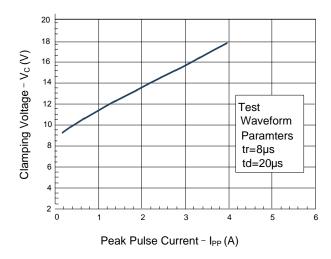
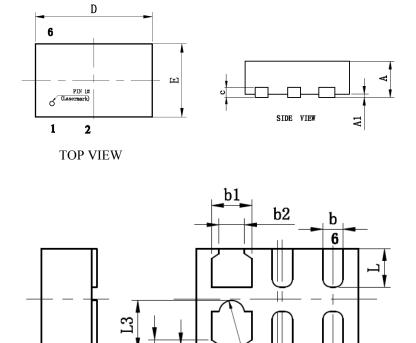


Figure 4: Clamping Voltage vs.lpp





Outline Drawing



SYMBOL	MILLIMETER		
SIMBOL	MIN	NOM	MAX
A	0. 50	0.55	0. 60
A 1	1	0.02	0. 05
ъ	0. 15	0.20	0. 25
ъ1	0. 35	0.40	0. 45
b2	0. 20	0.25	0. 30
С	0. 10	0. 15	0. 20
D	1. 55	1. 60	1. 65
e	0. 50BSC		
E	0. 95	1.00	1. 05
L	0. 33	0.38	0. 43
L1	0.100REF		
L2	0.05REF		
L3	0.49REF		
R	0. 08 0.13 0. 18		

Order information

Orderable Device	Package	Packing Option
MSESD0522P	SLP1610-4	3000PCS

BOTTOM VIEW



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